United States Patent [19]

Lee

[11] **Patent Number: Des. 318,630**

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[54] **PRINTED CIRCUIT BOARD TESTER**

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[**] Term: **14 Years**

[21] Appl. No.: **294,814**

[22] Filed: **Jan. 9, 1989**

[52] **U.S. Cl.** **D10/75**

[58] **Field of Search** .... D10/46, 75; 324/158 F

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Assistant Examiner—Antoine D. Davis
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[57] **CLAIM**

The ornamental design for a printed circuit board tester, as shown.

DESCRIPTION

FIG. 1 is a front elevational view of a printed circuit board tester showing my new design;

FIG. 2 is a right side elevational view;

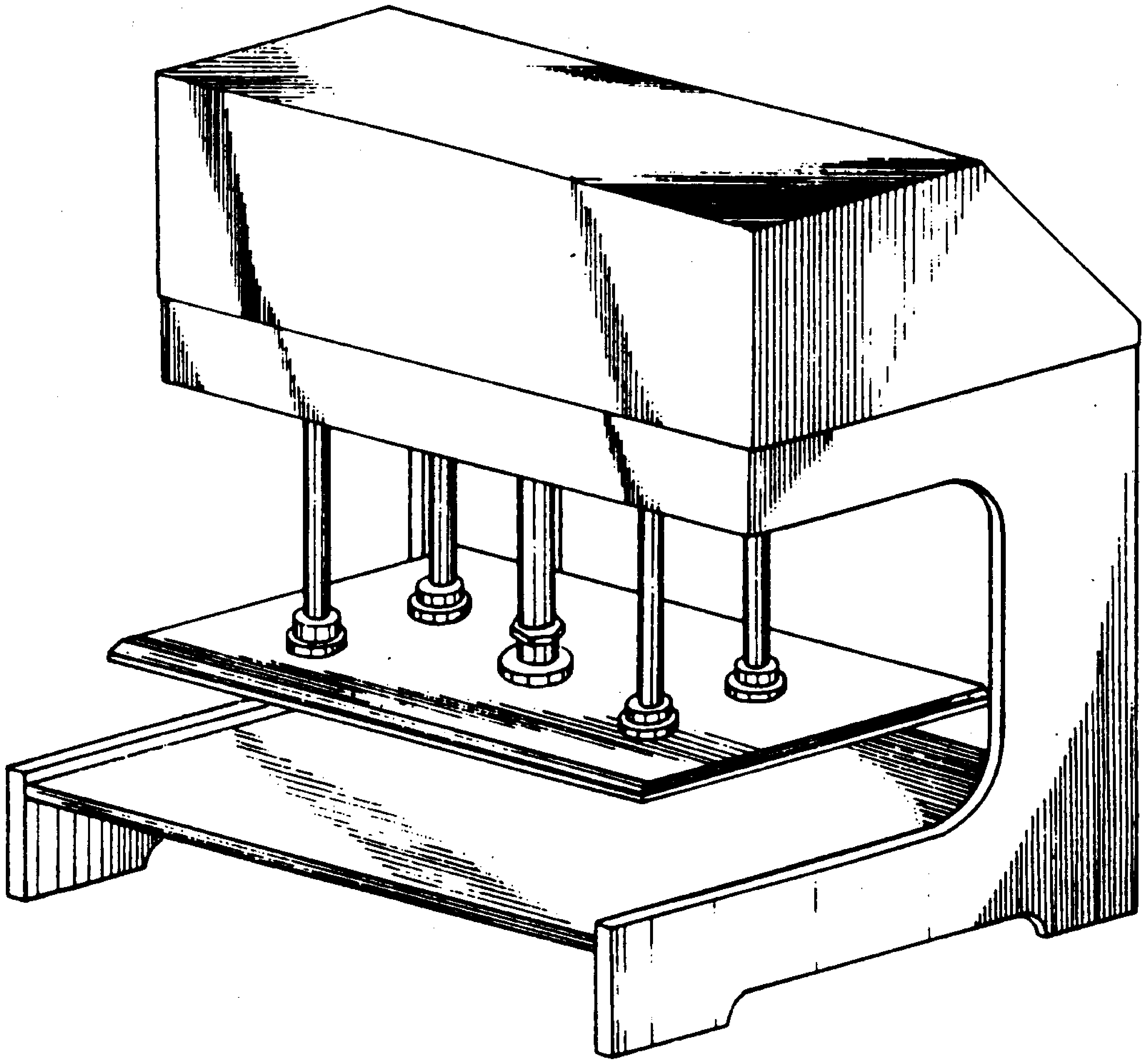
FIG. 3 is a left side elevational view;

FIG. 4 is a top plan view;

FIG. 5 is a rear elevational view;

FIG. 6 is a bottom plan view; and

FIG. 7 is a top, front and right side perspective view thereof.



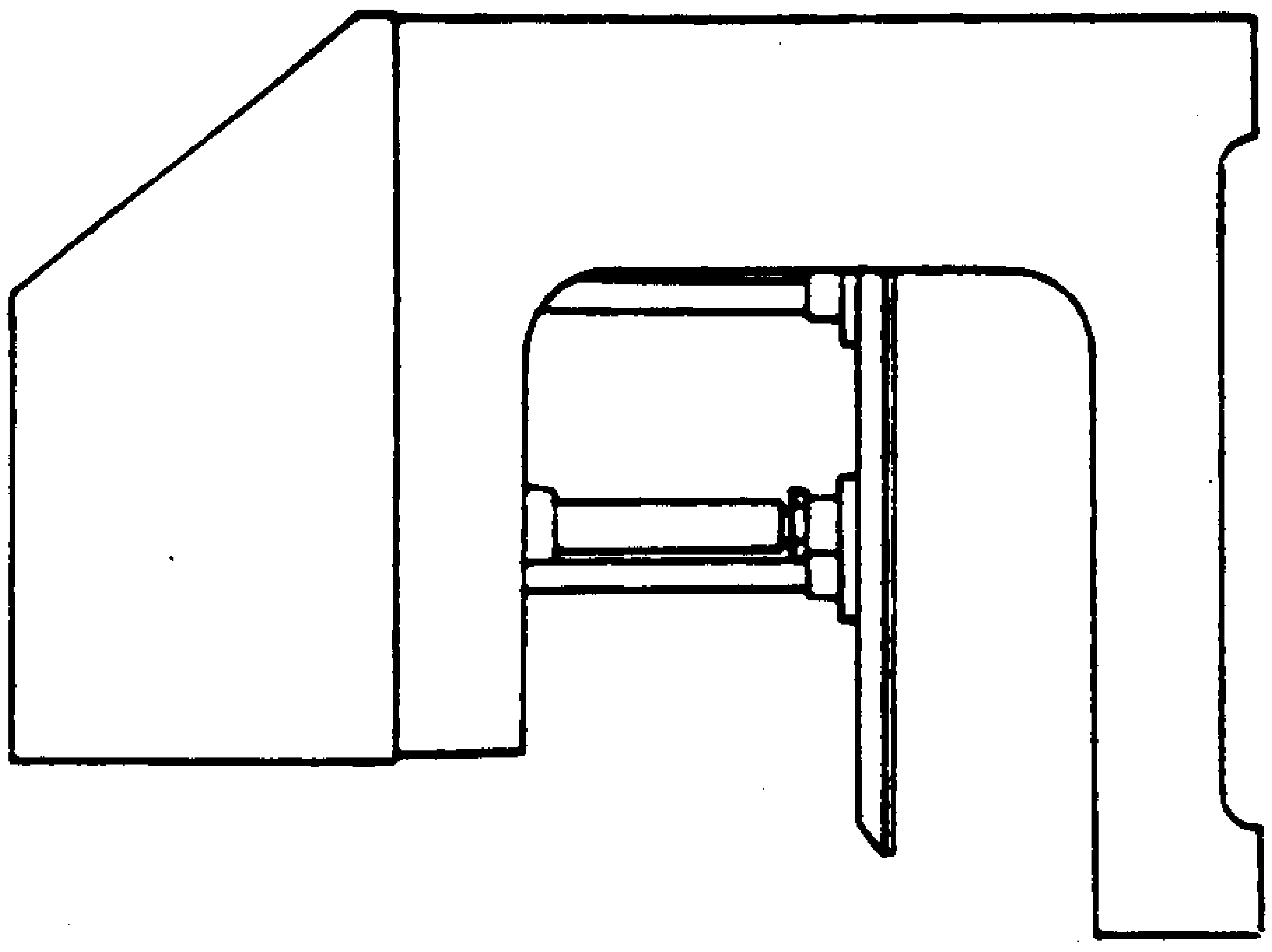


FIG:2

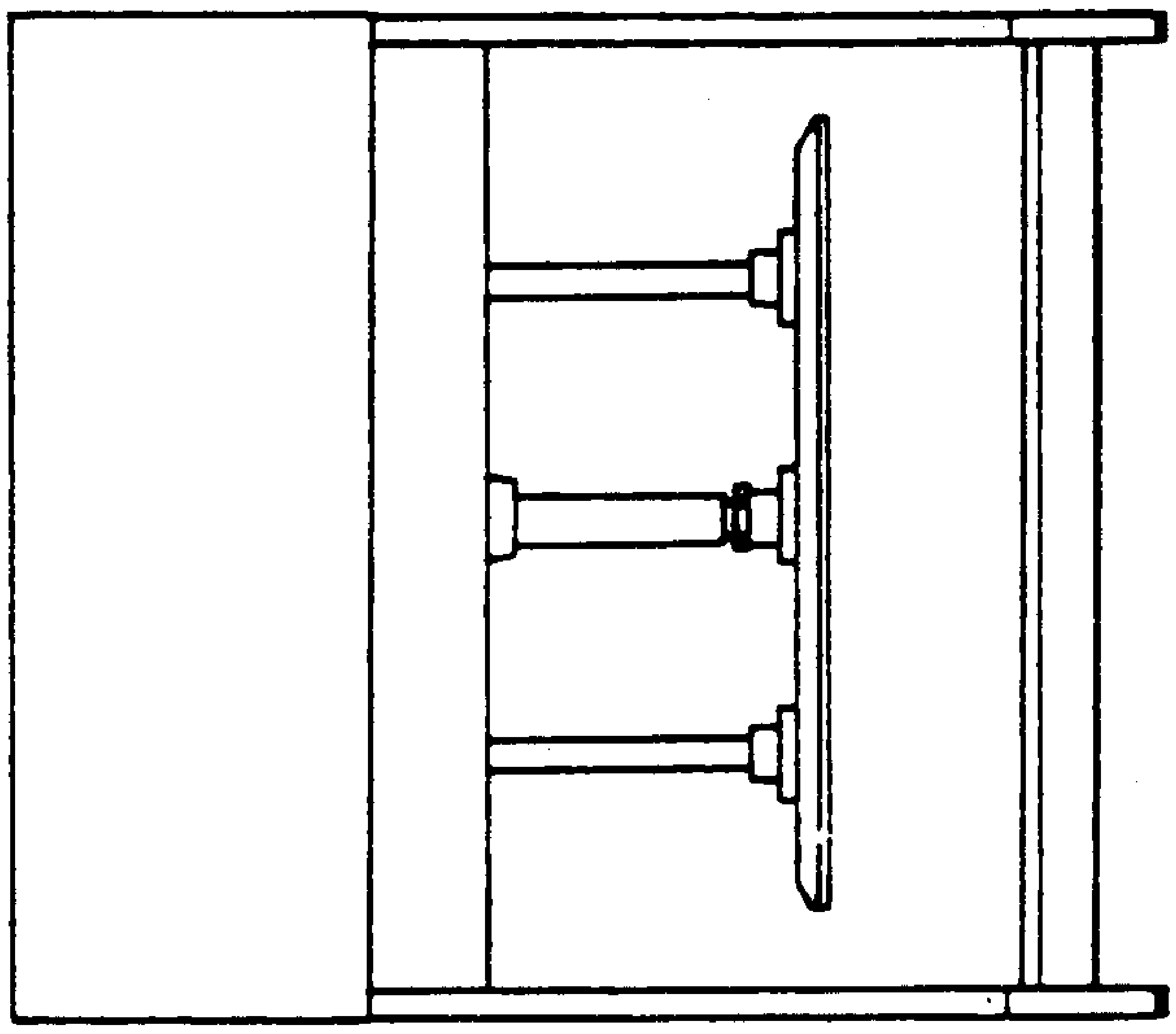


FIG:1

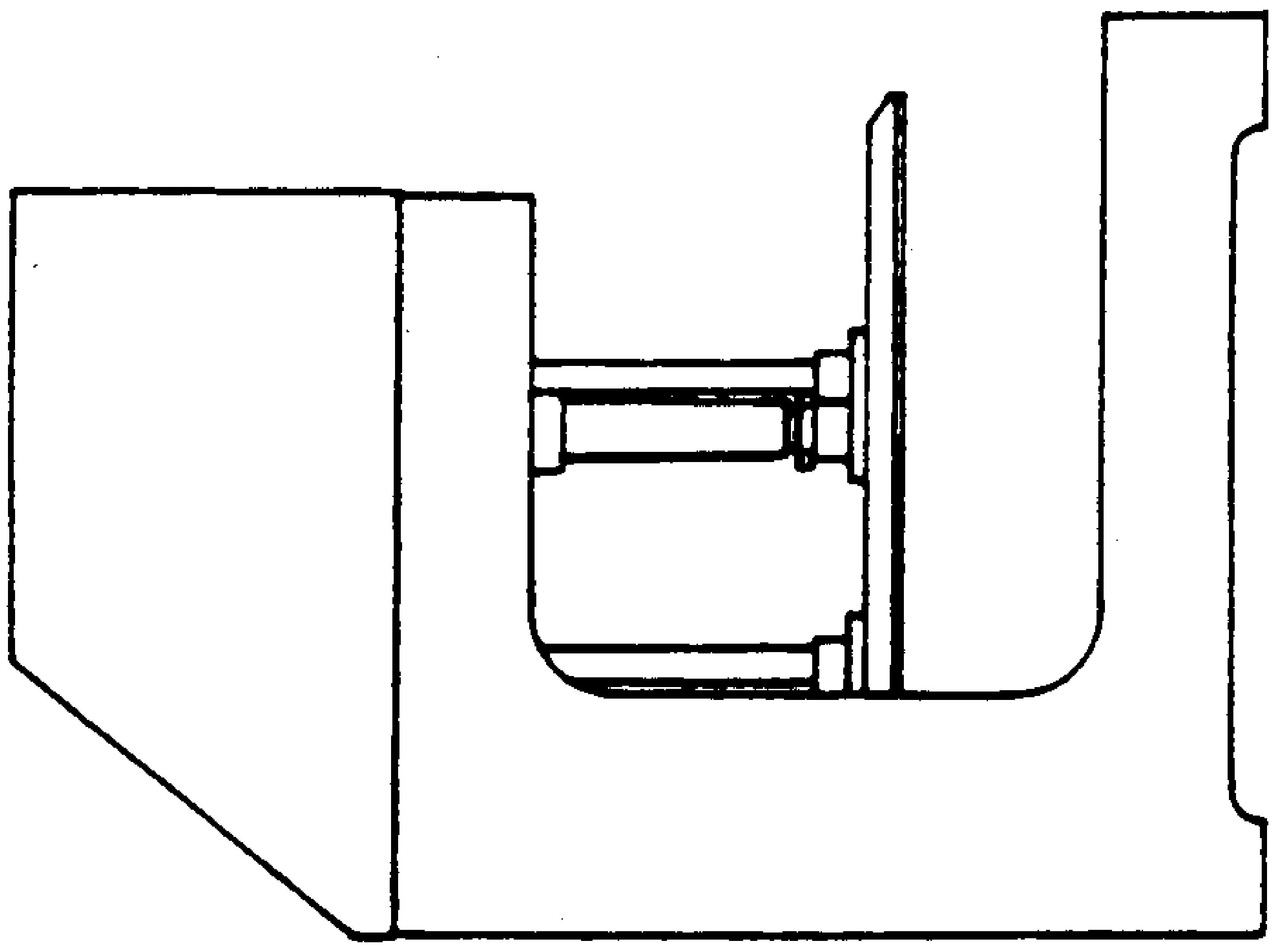


FIG:3

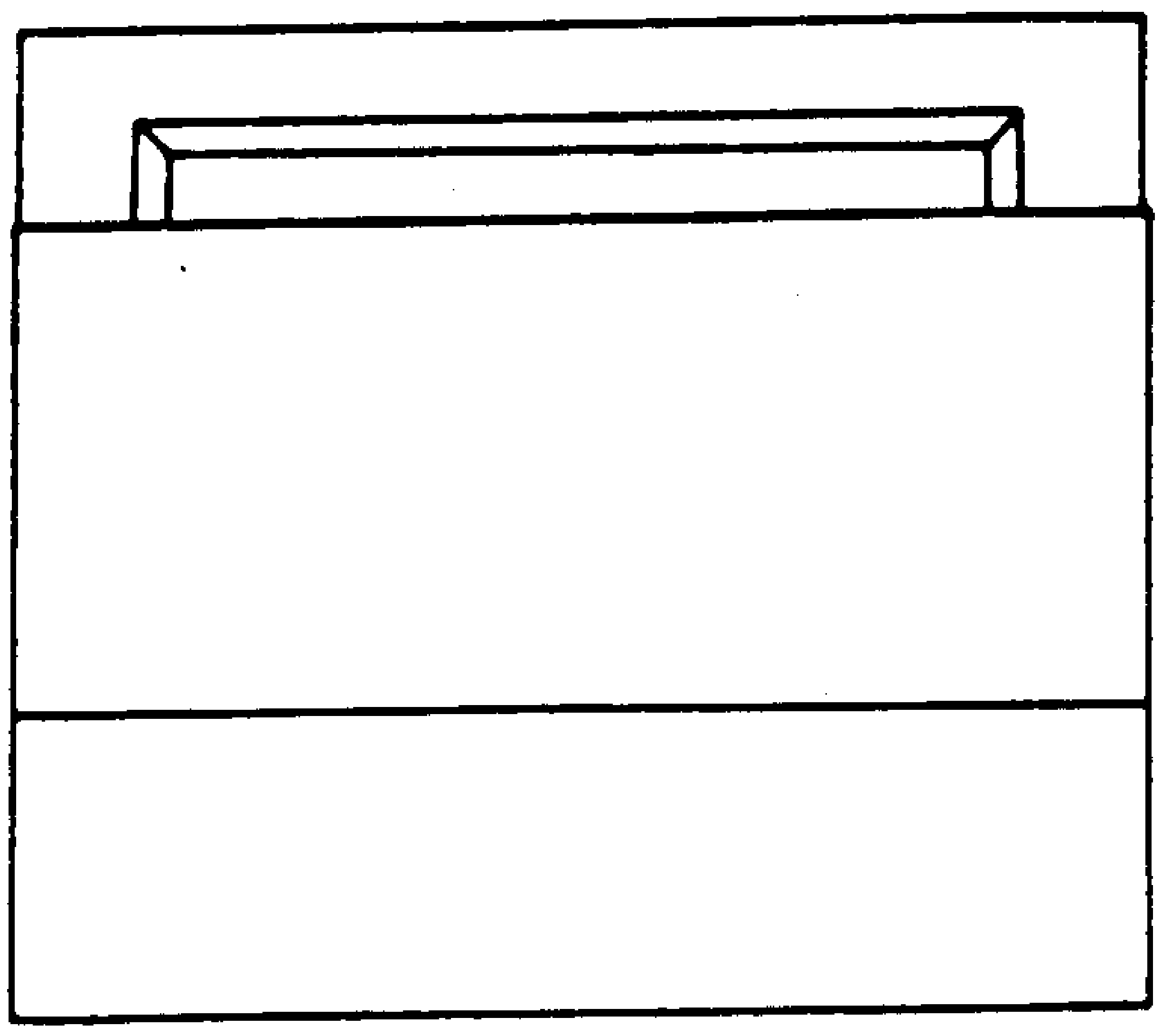


FIG:4

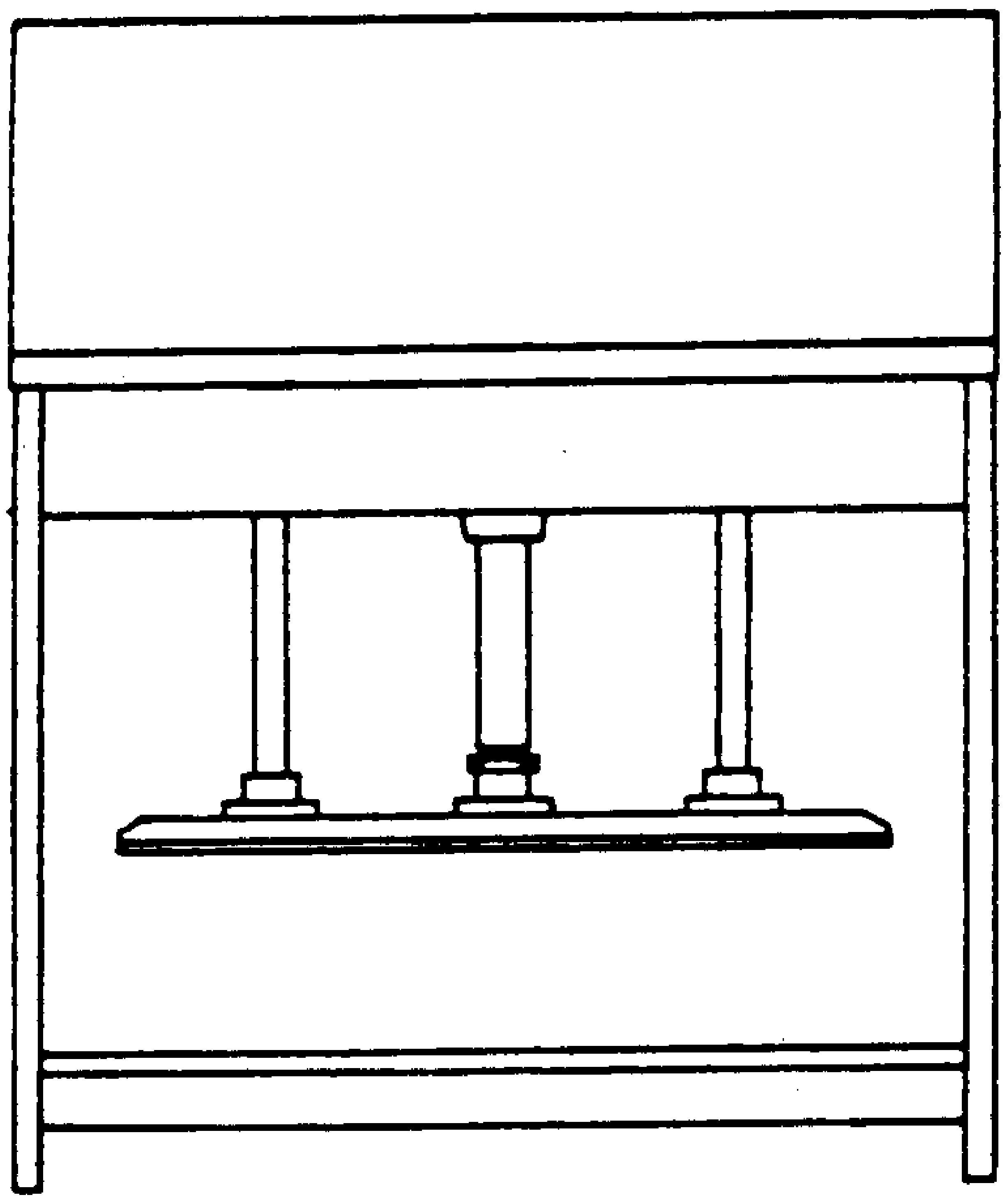


FIG:5

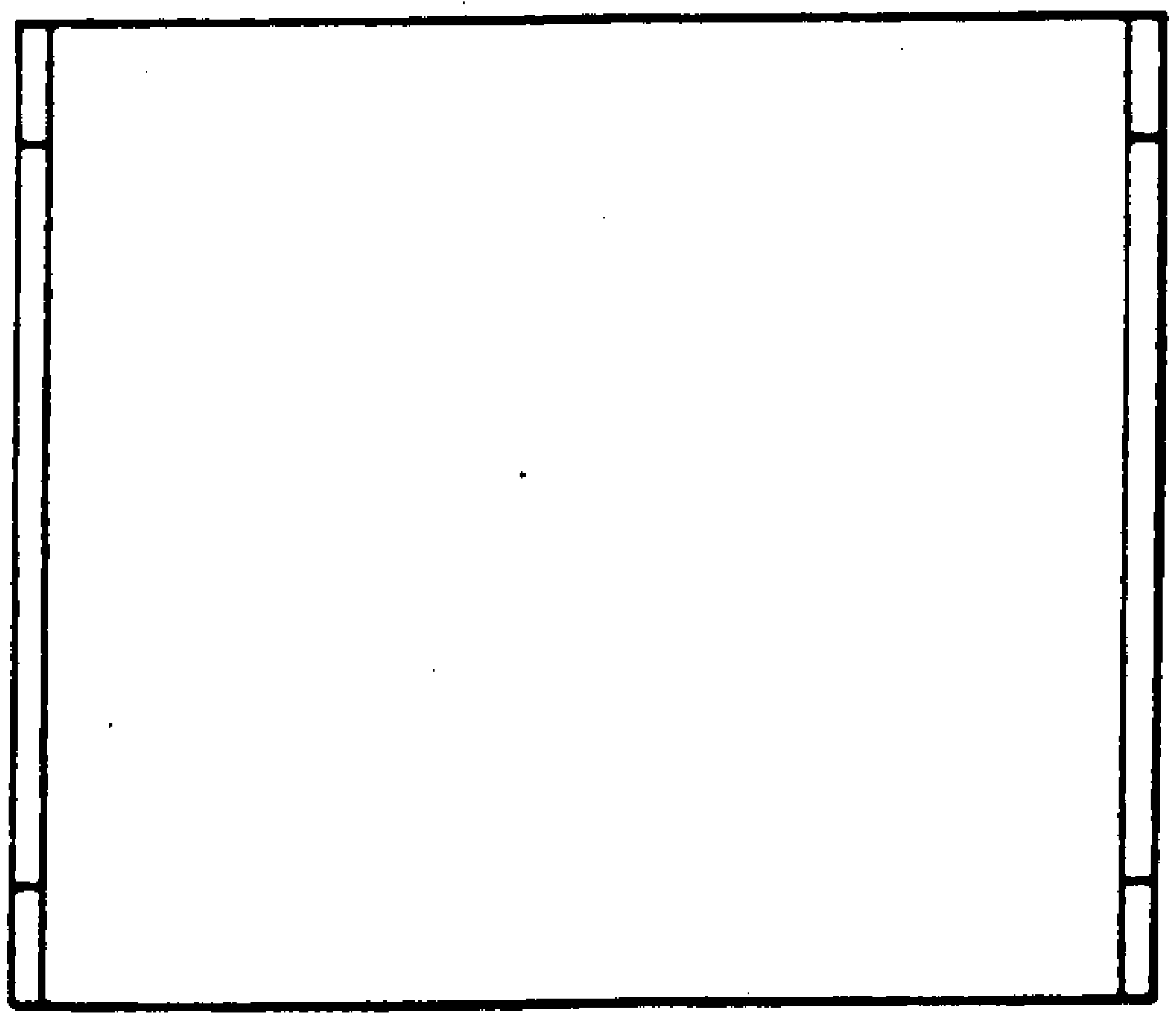


FIG:6

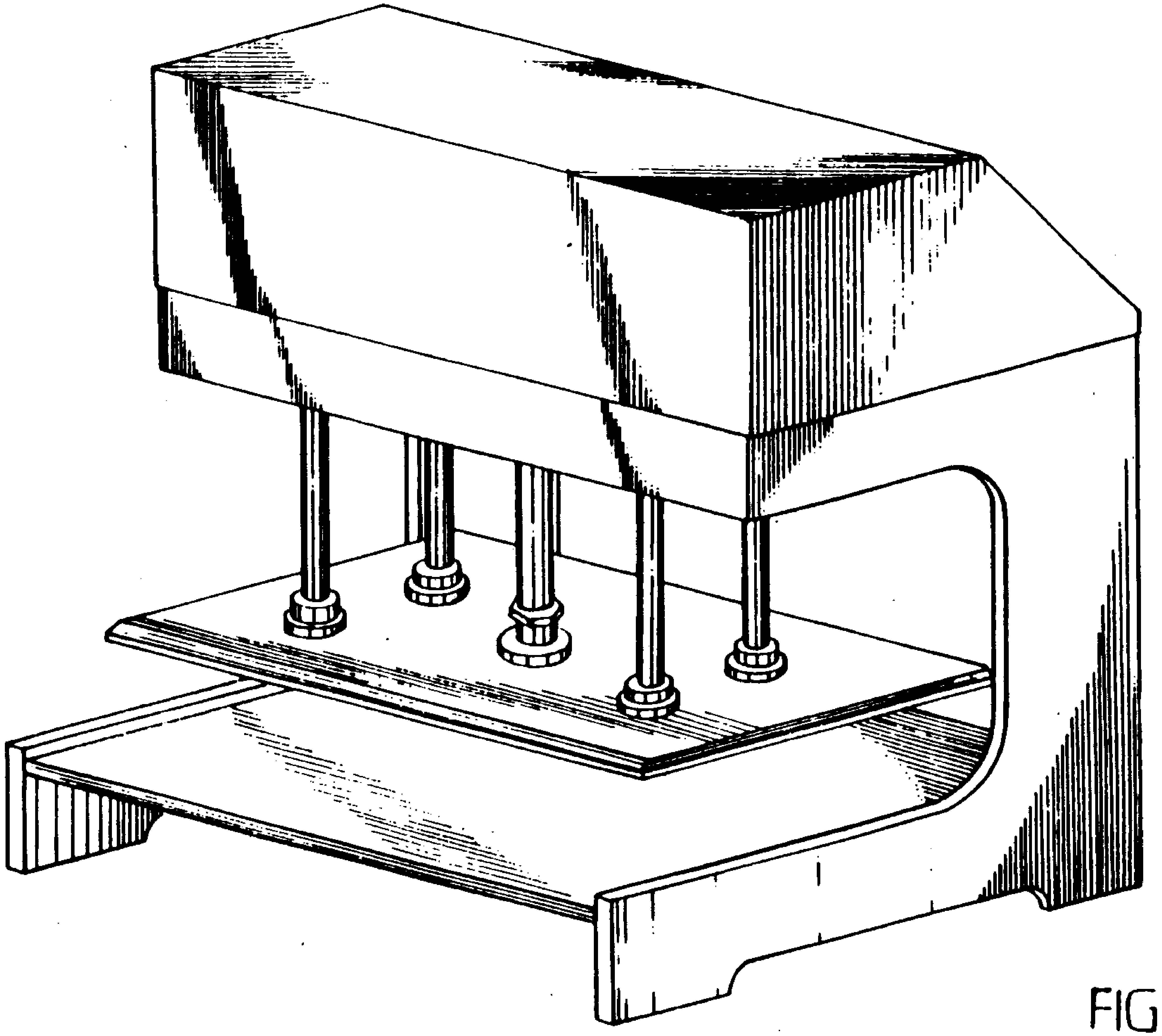


FIG 7